

EMC

Measurement and Test Report

For

GlobTek, Inc.

186 Veterans Dr. Northvale, NJ 07647 USA

Test Standards:	EN 55032:2012+AC:2013 EN 61000-3-2:2014 EN 61000-3-3:2013 <u>EN 55024:2010</u>
Product Description:	<u>ITE Power Supply</u>
Tested Model:	<u>GT-96600-7056-T3-AP</u>
Report No.:	<u>STR17038295E</u>
Tested Date:	<u>2017-03-27 to 2017-04-11</u>
Issued Date:	<u>2017-04-11</u>
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Note: This test report is limited to the above client company and the product model only. It may not be duplicated without prior permitted by Shenzhen SEM.Test Technology Co., Ltd.

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EMM TEST

1. GENERAL INFORMATION

1.1 Product Description for Equipment Under Test (EUT)

Client Information

Applicant: GlobTek, Inc.
 Address of applicant: 186 Veterans Dr. Northvale, NJ 07647 USA

Manufacturer: 1. GlobTek, Inc.
 2. GlobTek (Suzhou) Co., Ltd
 Address of manufacturer: 1. 186 Veterans Dr. Northvale, NJ 07647 USA
 2. Building 4, No. 76, Jin Ling East Rd., Suzhou Industrial Park, Suzhou, JiangSu 215021, China

General Description of EUT	
Product Name:	ITE Power Supply
Trade Name:	GlobTek
Model No.:	GT-96600-7056-T3-AP
Adding Model(s):	<p>GT*96600-*56***</p> <p>The 1st "*" part can be 'M' or '-' or 'H' for market identification and not related to safety.</p> <p>The 2nd "*" denotes the rated output wattage designation, which can be "01" to "70", with interval of 1.</p> <p>The 3rd "*" =-T2 means desktop class II with C8 AC inlet =-T2A means desktop class II with C18 AC inlet =-T3 means desktop class I with C14 AC inlet =-T3A means desktop class I with C6 AC inlet</p> <p>The 4th "*" =-AP or -PPor -SP</p> <p>-AP (with baby board) stands for Active POE -PP(no baby board) stands for Passive POE -SP (no baby board) stands for Simple POE</p> <p>The last * denote any six character = 0-9 or A-Z or ()[] or – or blank for marketing purposes.</p>
<p><i>Note: The test data is gathered from a production sample, provided by the manufacturer. The appearance of others models listed in the report is different from main-test model GT-96600-7056-T3-AP, but the circuit and the electronic construction do not change, declared by the manufacturer.</i></p>	

Technical Characteristics of EUT	
Rated Voltage:	AC 100-240V
Rated Current:	2.0A
Rated Power:	70W
Power Adaptor Model:	/
Highest Internal Frequency:	Below 108MHz
Classification of Equipment:	Class B

EMM TEST

1.2 Test Standards

The following report is prepared on behalf of the GlobTek, Inc. in accordance with EN55032, Electromagnetic compatibility of multimedia equipment - Emission requirements, and EN61000-3-2, Electromagnetic compatibility (EMC) -- Part 3-2: Limits - Limits for harmonic current emissions (equipment input current up to and including 16 A per phase), and EN61000-3-3, Electromagnetic compatibility (EMC) -- Part 3-3: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current \leq 16 A per phase and not subject to conditional connection, and EN55024, Immunity characteristics Limits and methods of measurement.

The objective of the manufacturer is to demonstrate compliance with the standards EN55032, EN61000-3-2, EN61000-3-3, and EN55024 for multimedia equipment.

Maintenance of compliance is the responsibility of the manufacturer. Any modification of the product maybe which result in lowering the emission/immunity should be checked to ensure compliance has been maintained.

1.3 Test Methodology

All measurements contained in this report were conducted with the standards EN55032, EN61000-3-2, EN61000-3-3, and EN55024 for Information Technology Equipment, and all related testing and measurement techniques intentional standards.

1.4 Test Facility

FCC – Registration No.: 934118

Shenzhen SEM.Test Technology Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files and the Registration is 934118.

Industry Canada (IC) Registration No.: 11464A

The 3m Semi-anechoic chamber of Shenzhen SEM.Test Technology Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 11464A.

CNAS Registration No.: L4062

Shenzhen SEM.Test Technology Co., Ltd. is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L4062. All measurement facilities used to collect the measurement data are located at 1/F, Building A, Hongwei Industrial Park, Liuxian 2nd Road, Bao'an District, Shenzhen, P.R.C (518101).

1.5 EUT Setup and Operation Mode

The equipment under test (EUT) was configured to measure its highest possible emission/immunity level. The test modes were adapted according to the operation manual for use, more detailed description as follows:

Test Mode List:

Test Mode	Description	Remark
TM1	Working	/

Note: The product is Measurement at two nominal voltages of 230V and 110V, using a frequency of 50Hz or 60Hz. This report is display the worst case with 230V/50Hz data.

EUT Cable List and Details

Cable Description	Length (M)	Shielded/Unshielded	With Core/Without Core
/	/	/	/

Auxiliary Equipment List and Details

Description	Manufacturer	Model	Serial Number
/	/	/	/

Special Cable List and Details

Cable Description	Length (M)	Shielded/Unshielded	With Core/Without Core
AC Cable	0.6	Unshielded	Without Core

1.6 Performance Criteria for EMS

All the test data has been collected, reduced, and analyzed within this report in accordance with Immunity requires the following as specific performance criteria:

- A. The apparatus shall continue to operate as intended during and after the test. The manufacturer specifies some minimum performance level. The performance level may be specified by the manufacturer as a permissible loss of performance.
- B. The apparatus shall continue to operate as intended after the test. This indicates that the EUT does not need to function at normal performance levels during the test, but must recover. Again some minimal performance is defined by the manufacture. No change in operating state or loss or data is permitted.
- C. Temporary loss of function is allowed. Operation of the EUT may stop as long as it is either automatically reset or can be manually restored by operation of the controls.

1.7 Test Equipment List and Details

No.	Description	Manufacturer	Model	Serial No.	Cal Date	Due. Date
SEMT-1031	Spectrum Analyzer	Rohde & Schwarz	FSP	836079/035	2016-06-04	2017-06-03
SEMT-1007	EMI Test Receiver	Rohde & Schwarz	ESVB	825471/005	2016-06-04	2017-06-03
SEMT-1008	Amplifier	Agilent	8447F	3113A06717	2016-06-04	2017-06-03
SEMT-1043	Amplifier	C&D	PAP-1G18	2002	2016-06-04	2017-06-03
SEMT-1011	Trilog Broadband Antenna	Schwarz beck	VULB9163	9163-333	2016-06-04	2017-06-03
SEMT-1068	Trilog Broadband Antenna	Schwarz beck	VULB9163(B)	9163-333	2016-06-04	2017-06-03
SEMT-1042	Horn Antenna	ETS	3117	00086197	2016-06-04	2017-06-03
SEMT-1069	Loop Antenna	Schwarz beck	FMZB 1516	9773	2016-06-04	2017-06-03
SEMT-1001	EMI Test Receiver	Rohde & Schwarz	ESPI	101611	2016-06-04	2017-06-03
SEMT-1066	EMI Test Receiver	Rohde & Schwarz	ESPI	101391	2016-06-04	2017-06-03
SEMT-1002	Pulse Limiter	Rohde & Schwarz	ESH3-Z2	100911	2016-06-04	2017-06-03
SEMT-1003	AC LISN	Schwarz beck	NSLK8126	8126-224	2016-06-04	2017-06-03
SEMT-1060	DC LISN	Schwarz beck	NNBM8126D	279	2016-06-04	2017-06-03
SEMT-1061	DC LISN	Schwarz beck	NNBM8126D	280	2016-06-04	2017-06-03
SEMT-1085	8-WIRE LISN	Schwarz beck	8158	CAT3-8158-0059	2016-06-04	2017-06-03
SEMT-1086	8-WIRE LISN	Schwarz beck	8158	CAT5-8158-0117	2016-06-04	2017-06-03
SEMT-1005	Clamp	Schwarz beck	MDS21	3809	2016-06-04	2017-06-03
SEMT-1014	Loop Antenna	EVERFINE	LLA-2	711001	2016-06-04	2017-06-03
SEMT-1071	VDH Test Head	AFJ	VDH 30	SC022Z	2016-06-04	2017-06-03
SEMT-1056	Digital Power Analyzer	California Instrument	CTS	72831	2016-06-04	2017-06-03
SEMT-1057	Power Source	California Instrument	5001IX-CTS-400	25965	2016-06-04	2017-06-03
SEMT-1027	ESD Generator	TESQ AG	NSG 437	161	2016-06-04	2017-06-03
SEMT-1055	Signal Generator	HP	8648A	3642U01277	2016-06-04	2017-06-03
SEMT-1008	Amplifier	Agilent	8447F	3113A06717	2016-06-04	2017-06-03
SEMT-1067	Amplifier	Agilent	8447D	2944A10179	2016-06-04	2017-06-03
SEMT-1024	Transient 2000	EMC PARTNER	TRA2000	863	2016-06-04	2017-06-03
SEMT-1045	CS Immunity Tester	EMTEST	CWS500	0900-03	2016-06-04	2017-06-03

2. SUMMARY OF TEST RESULTS

Standards	Description of Test Item	Result
EN55032	Conducted Emission	Compliant
	Radiated Emission	Compliant
EN61000-3-2	Harmonic Current Emission	Compliant
EN61000-3-3	Voltage Fluctuation and Flicker	Compliant
EN55024	Electrostatic Discharge Immunity in accordance with IEC 61000-4-2	Compliant
	Continuous Radiated Disturbances Immunity in accordance with IEC 61000-4-3	Compliant
	Electrical Fast Transient/Burst Immunity in accordance with IEC 61000-4-4	Compliant
	Surges Immunity in accordance with IEC 61000-4-5	Compliant
	Continuous Conducted Disturbances Immunity in accordance with IEC 61000-4-6	Compliant
	Power-frequency Magnetic Fields Immunity in accordance with IEC 61000-4-8	N/A
	Voltage Dips/Interruptions Immunity in accordance with IEC 61000-4-11	Compliant

N/A: not applicable

3. Conducted Emission

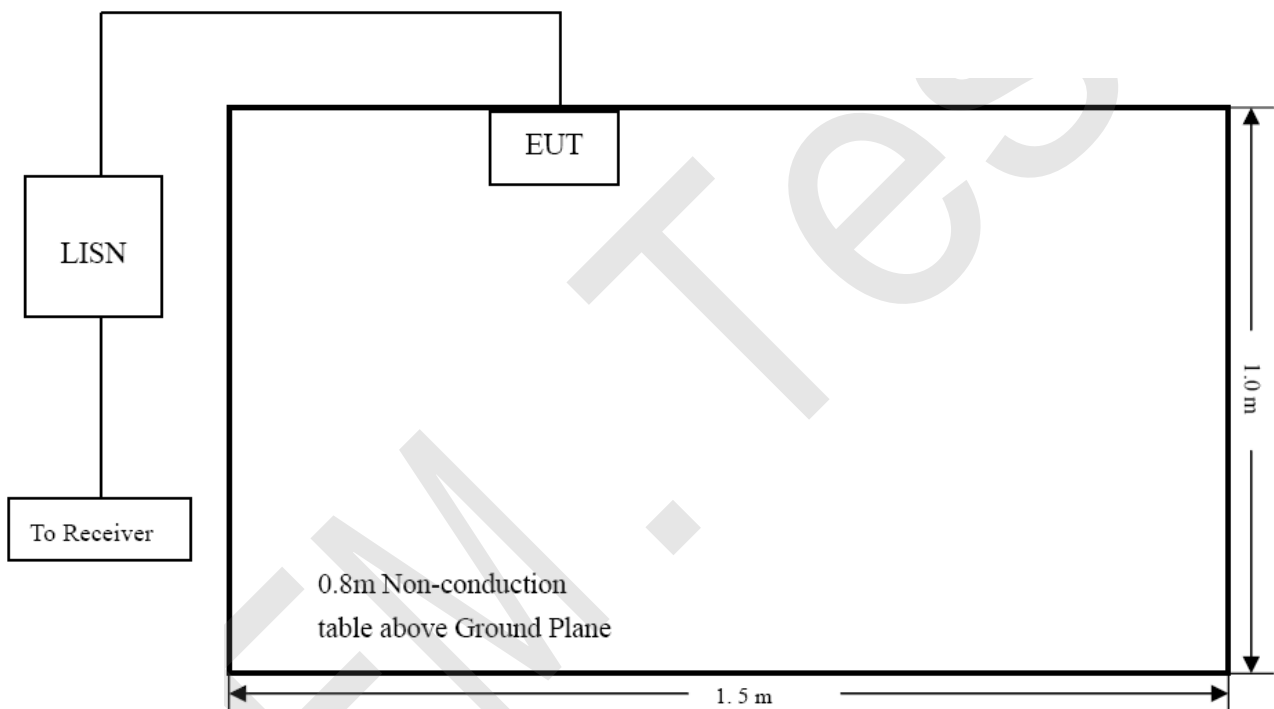
3.1 Measurement Uncertainty

Base on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any conducted emissions measurement is ± 2.88 dB.

3.2 Test Procedure

Test is conducting under the description of EN55032 Annex A.3.5.

3.3 Basic Test Setup Block Diagram



3.4 Environmental Conditions

Temperature:	22 ° C
Relative Humidity:	55 %
ATM Pressure:	1015 mbar

3.5 Summary of Test Results/Plots

According to the data in section 3.6, the EUT complied with the EN55032 Conducted margin for a Class B device, with the *worst* margin reading of:

-15.59 dB at 0.5580 MHz in the Line mode, QP detector, 0.15-30MHz

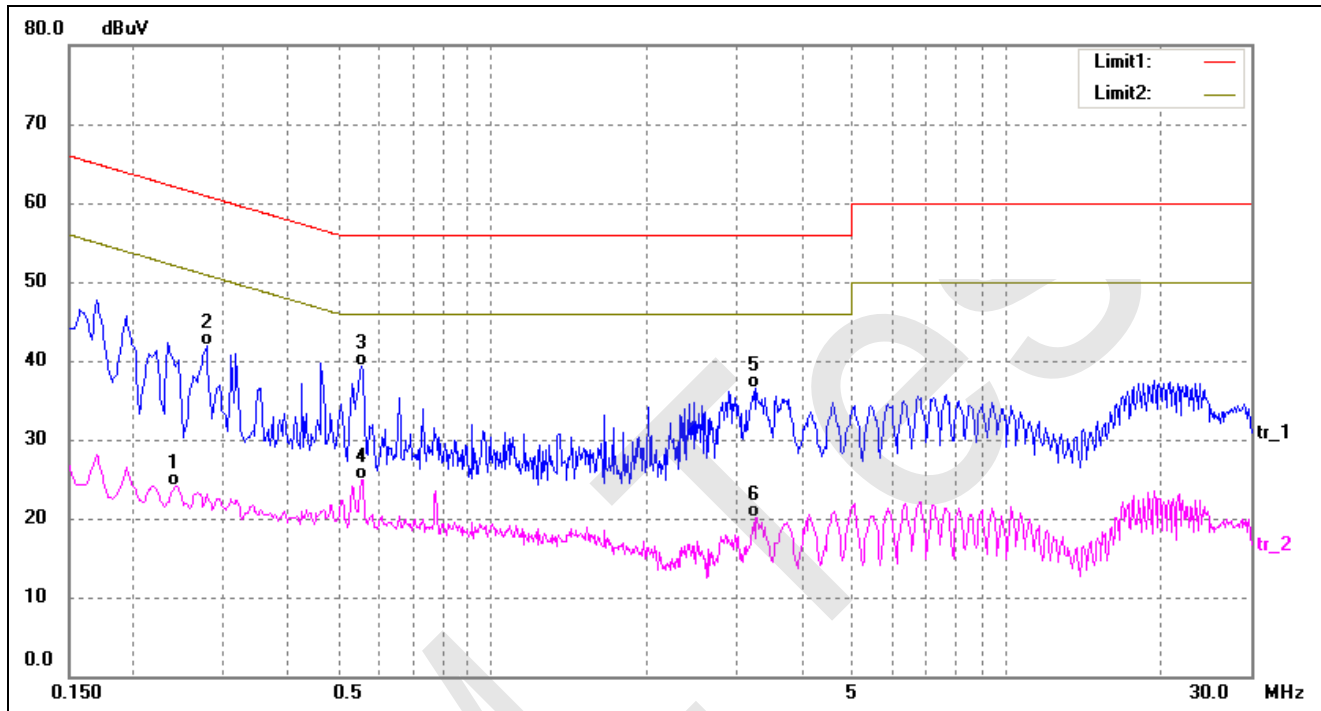
3.6 Conducted Emissions Test Data

EMC TEST

Plot of Conducted Emissions Test Data

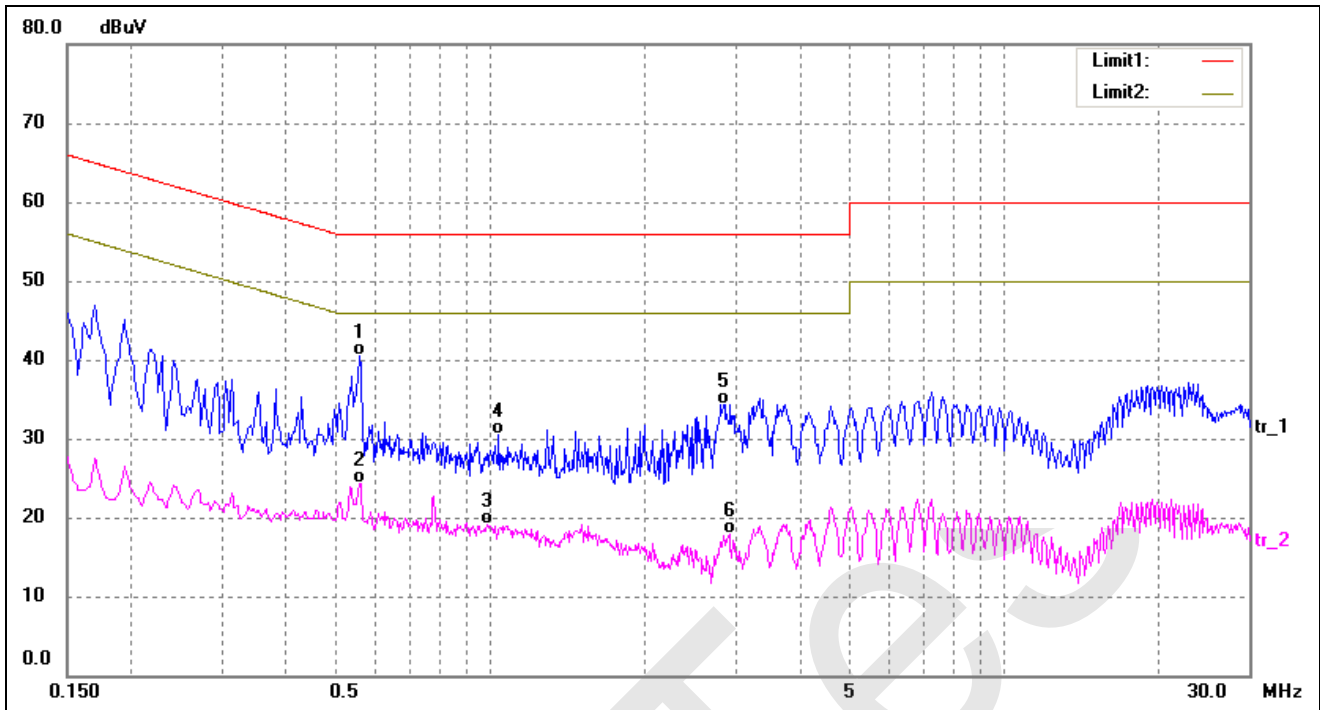
EUT: *ITE Power Supply*
 Tested Model: *GT-96600-7056-T3-AP*
 Operating Condition: *TM1*
 Comment: *AC 230V/50Hz*

Test Specification: *Neutral*



No.	Frequency (MHz)	Reading (dBuV)	Correct (dB/m)	Result (dBuV)	Limit (dBuV)	Margin (dB)	Detector
1	0.2420	14.31	9.80	24.11	52.03	-27.92	AVG
2	0.2780	32.01	9.80	41.81	60.88	-19.07	QP
3*	0.5580	29.47	9.80	39.27	56.00	-16.73	QP
4	0.5580	15.03	9.80	24.83	46.00	-21.17	AVG
5	3.2620	26.73	9.70	36.43	56.00	-19.57	QP
6	3.2620	10.45	9.70	20.15	46.00	-25.85	AVG

Test Specification: Line



No.	Frequency (MHz)	Reading (dBuV)	Correct (dB/m)	Result (dBuV)	Limit (dBuV)	Margin (dB)	Detector
1*	0.5580	30.61	9.80	40.41	56.00	-15.59	QP
2	0.5580	14.48	9.80	24.28	46.00	-21.72	AVG
3	0.9860	9.26	9.76	19.02	46.00	-26.98	AVG
4	1.0420	20.79	9.76	30.55	56.00	-25.45	QP
5	2.8220	24.63	9.71	34.34	56.00	-21.66	QP
6	2.9220	8.22	9.71	17.93	46.00	-28.07	AVG

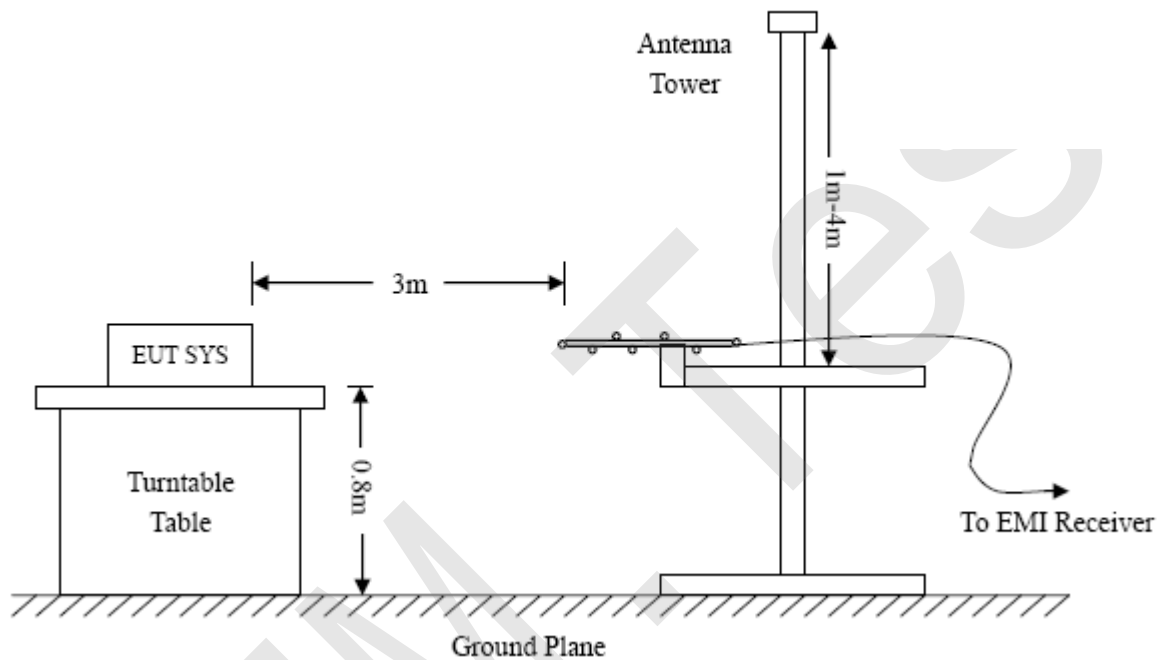
4. Radiated Emission

4.1 Measurement Uncertainty

Base on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any radiation emissions measurement is ± 5.10 dB.

4.2 Test Procedure

Test is conducting under the description of EN55032 Annex A.3.4.



4.3 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and the Cable Factor, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

$$\text{Corr. Ampl.} = \text{Indicated Reading} + \text{Antenna Factor} + \text{Cable Factor} - \text{Amplifier Gain}$$

The “**Margin**” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of $-6\text{dB}\mu\text{V}$ means the emission is $6\text{dB}\mu\text{V}$ below the maximum limit for Class B device. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Corr. Ampl.} - \text{EN55032 Class B Limit}$$

4.4 Environmental Conditions

Temperature:	23° C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

4.5 Summary of Test Results/Plots

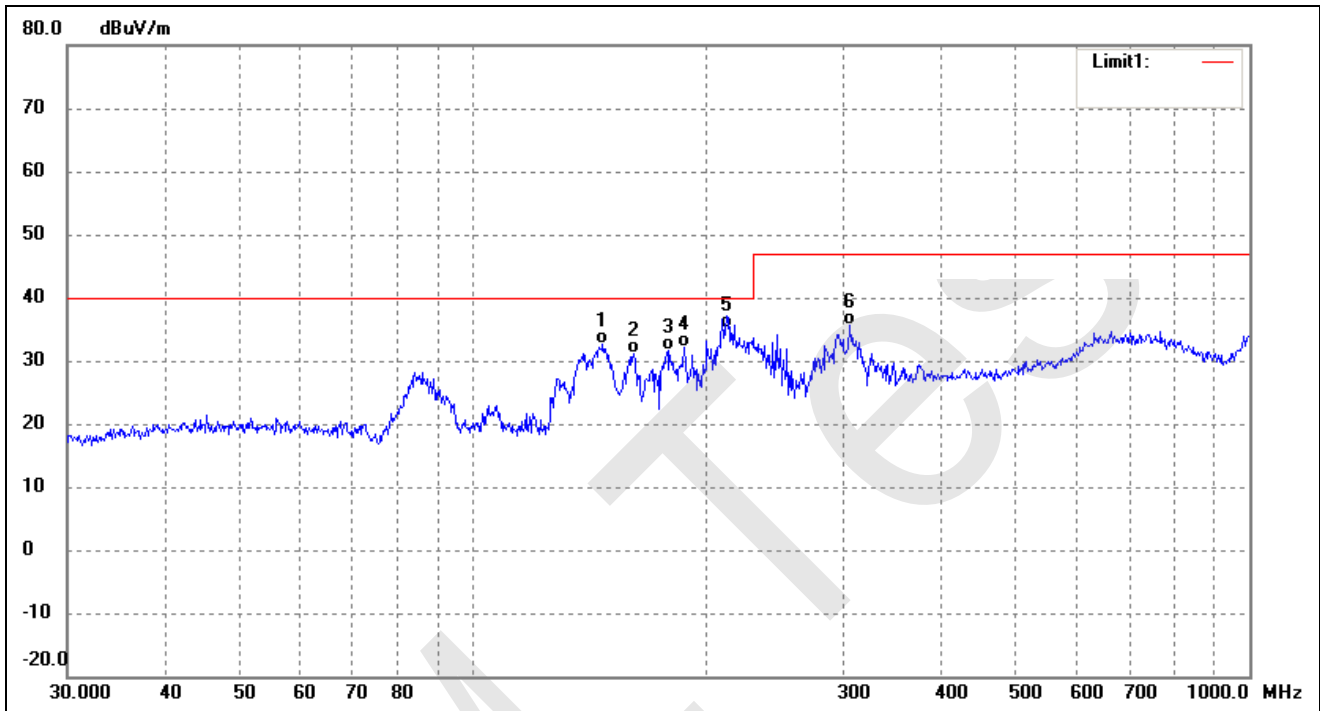
According to the data in section 4.5, the EUT complied with the EN55032 Class B standards, and had the worst margin is:

-4.91 dB at 212.2695 MHz in the Horizontal polarization, 30 MHz to 1 GHz, 3Meters

Plot of Radiated Emissions Test Data

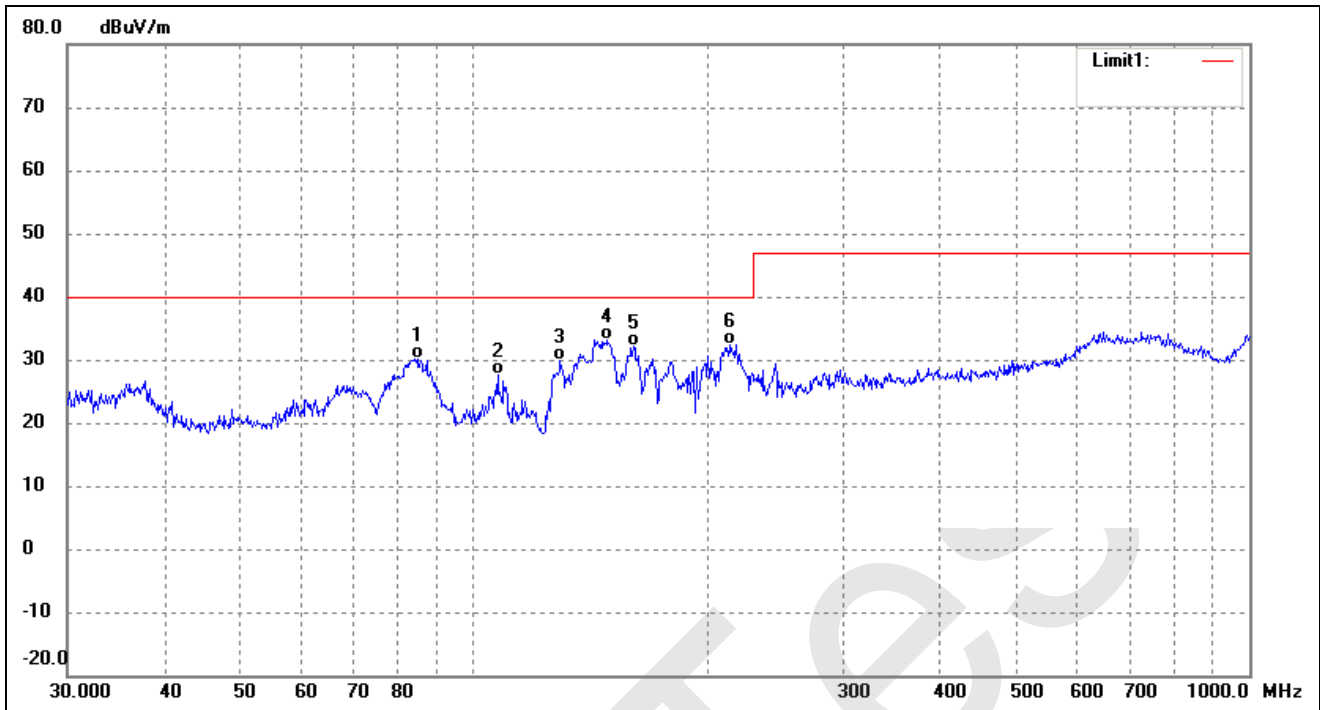
EUT: *ITE Power Supply*
 Tested Model: *GT-96600-7056-T3-AP*
 Operating Condition: *TM1*
 Comment: *AC 230V/50Hz*

 Test Specification: *Horizontal*



No.	Frequency (MHz)	Reading (dBuV/m)	Correct dB/m	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Degree ()	Height (cm)	Remark
1	146.8877	29.83	2.88	32.71	40.00	-7.29	76	100	QP
2	160.9089	28.68	2.41	31.09	40.00	-8.91	119	100	QP
3	178.1327	29.24	2.46	31.70	40.00	-8.30	98	100	QP
4	187.0958	29.38	2.76	32.14	40.00	-7.86	333	100	QP
5	212.2695	29.07	6.02	35.09	40.00	-4.91	352	100	QP
6	305.6800	23.58	11.94	35.52	47.00	-11.48	199	100	QP

Test Specification: Vertical



No.	Frequency (MHz)	Reading (dBuV/m)	Correct (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Degree ()	Height (cm)	Remark
1	84.7019	27.59	2.50	30.09	40.00	-9.91	244	100	QP
2	107.5101	22.71	4.87	27.58	40.00	-12.42	295	100	QP
3	129.4678	25.78	4.03	29.81	40.00	-10.19	76	100	QP
4	148.9625	30.32	2.80	33.12	40.00	-6.88	205	100	QP
5	160.9089	29.68	2.41	32.09	40.00	-7.91	199	100	QP
6	213.7634	26.15	6.34	32.49	40.00	-7.51	181	100	QP

5. Harmonic Current Emissions

5.1 Test Procedure

Test is conducting under the description of EN61000-3-2.

5.2 Test Standards

EN61000-3-2, Clause 7.1 Limits for Class A equipment.

Environmental Conditions

Temperature:	22 °C
Relative Humidity:	48%
ATM Pressure:	1022 mbar

5.3 Harmonic Current Emissions Test Data

According to Clause 7 of EN61000-3-2, the rated power of the EUT is less than 75W, belong to 'equipment with a rated power of 75W or less', therefore 'limits are not specified in this edition of the standards'. It is deem to full fit the requirements of the standards.

Result: The EUT is compliance with the requirements of this section.

6. Voltage Fluctuation Flicker

6.1 Test Procedure

Test is conducting under the description of EN61000-3-3.

6.2 Test Standards

EN61000-3-3, Limit: Clause 5.

Environmental Conditions

Temperature:	22 °C
Relative Humidity:	48%
ATM Pressure:	1022 mbar

6.3 Voltage Fluctuation and Flicker Test Data

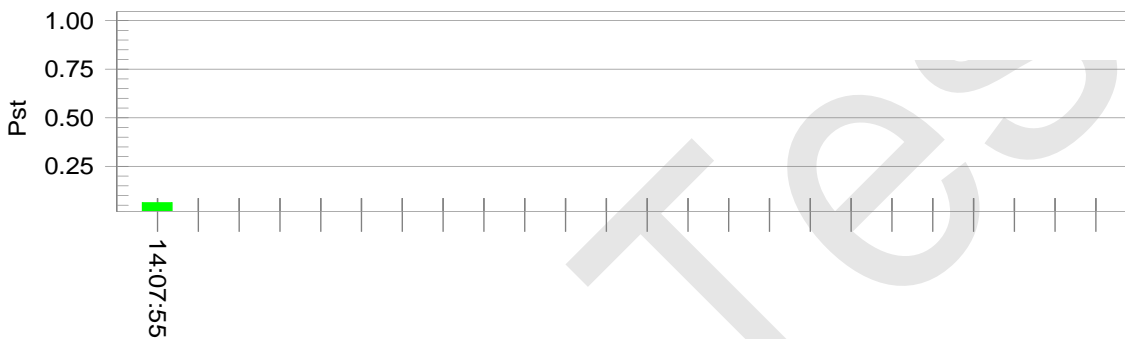
Flicker Test Summary per EN/IEC61000-3-3 (Run time)

EUT: ITE Power Supply		Tested by: Terry
Test category: All parameters (European limits)		Test Margin: 100
Test date: 2017-04-06	Start time: 01:57:35 PM	End time: 02:07:56 PM
Test duration (min): 10	Data file name: F-000208.cts_data	
Comment: TM1		
Customer: GlobTek, Inc.		

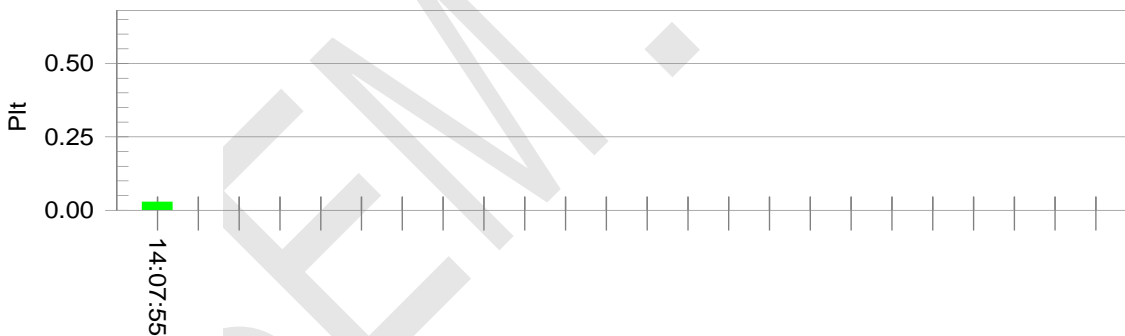
Test Result: Pass
Status: Test Completed

Pst_i and limit line

European Limits



Plt and limit line



Parameter values recorded during the test:

Vrms at the end of test (Volt):	229.76			
Highest dt (%):	0.00	Test limit (%):	3.30	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.00	Test limit (%):	3.30	Pass
Highest dmax (%):	0.00	Test limit (%):	4.00	Pass
Highest Pst (10 min. period):	0.064	Test limit:	1.000	Pass
Highest Plt (2 hr. period):	0.028	Test limit:	0.650	Pass

7. Electrostatic Discharges (ESD)

7.1 Test Procedure

Test is conducting under the description of IEC61000-4-2.

Test Performance

Performance Criterion: B

Environmental Conditions

Temperature:	26 °C
Relative Humidity:	55%
ATM Pressure:	1011 mbar

7.2 Electrostatic Discharge Immunity Test Data

Table 1: Electrostatic Discharge Immunity (Air Discharge)

EN 61000-4-2 Test Points	Test Levels (kV)									
	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
GAP	A	A	A	A	A	A	A	A		
Surface	A	A	A	A	A	A	A	A		

Table 2: Electrostatic Discharge Immunity (Direct Contact)

EN 61000-4-2 Test Points	Test Levels (kV)									
	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
METAL	A	A	A	A						

Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP)

EN 61000-4-2 Test Points	Test Levels (kV)									
	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
Front Side	A	A	A	A						
Top Side	A	A	A	A						
Back Side	A	A	A	A						
Left Side	A	A	A	A						
Right Side	A	A	A	A						

Table 4: Electrostatic Discharge Immunity (Indirect Contact VCP)

EN 61000-4-2 Test Points	Test Levels (kV)									
	-2	+2	-4	+4	-6	+6	-8	+8	-15	+15
Front Side	A	A	A	A						
Top Side	A	A	A	A						
Back Side	A	A	A	A						
Left Side	A	A	A	A						
Right Side	A	A	A	A						

Test Result: Pass

8. Continuous Radiated Disturbances (R/S)

8.1 Test Procedure

Test is conducting under the description of IEC61000-4-3.

Test Performance

Performance Criterion: A

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	52%
ATM Pressure:	1010 mbar

8.2 Continuous Radiated Disturbances Test Data

Frequency step: 1% of fundamental

Dwell time: 1 second

Modulation: AM by 1kHz sine wave with 80% modulation depth

Frequency Range(MHz)	Field (V/m)	Front		Rear		Left Side		Right Side	
		VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-1000	3	A	A	A	A	A	A	A	A

Test Result: Pass

9. Electrical Fast Transients (EFT)

9.1 Test Procedure

Test is conducting under the description of IEC61000-4-4.

Test Performance

Performance Criterion: B

Environmental Conditions

Temperature:	22 °C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

9.2 Electrical Fast Transients Test Data

EN 61000-4-4 Test Points		Test Levels (kV)							
		+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
Power Supply Power Port of EUT	L1	A	A	A	A	/	/	/	/
	L2	A	A	A	A	/	/	/	/
	PE	A	A	A	A	/	/	/	/
	L1+L2	A	A	A	A	/	/	/	/
	L1 + PE	A	A	A	A	/	/	/	/
	L2 + PE	A	A	A	A	/	/	/	/
	L1+L2+PE	A	A	A	A	/	/	/	/
Signal ports	/	/	/	/	/	/	/	/	

Test Result: Pass

10. Surges

10.1 Test Procedure

Test is conducting under the description of IEC 61000-4-5.

Test Performance

Performance Criterion: B

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

10.2 Surge Test Data

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	±	L-N, L-PE, N-PE	A	/
2	1kV	±	L-N, L-PE, N-PE	A	/
3	2kV	±	L-PE, N-PE	A	/
4	4kV	±	L-N, L-PE, N-PE	/	/

Test Result: Pass

11. Continuous Conducted Disturbances (C/S)

11.1 Test Procedure

Test is conducting under the description of IEC 61000-4-6.

Test Performance

Performance Criterion: A

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	53%
ATM Pressure:	1011 mbar

11.2 Continuous Conducted Disturbances Test Data

Sweep frequency range: 150kHz~80MHz

Frequency step: 1% of fundamental

Dwell time: 1 second

Level	Voltage Level (e.m.f.) U_0	Modulation:	Pass	Fail
1	1	AM 80%, 1kHz sinewave	/	/
2	3	AM 80%, 1kHz sinewave	A	/
3	10	AM 80%, 1kHz sinewave	/	/
X	Special	/	/	/

Test Result: Pass

12. Voltage Dips and Interruptions

12.1 Test Procedure

Test is conducting under the description of IEC 61000-4-11.

Test Performance

Performance Criterion: B/C

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	50%
ATM Pressure:	1011 mbar

12.2 Voltage Dips And Interruptions Test Data

U: Voltage dips in % U_T (U_T is rated voltage for the EUT)




T: Test duration

Level	U	T	Phase Angle	N	Pass	Fail
1	100%	10ms	0/90/180/270	3	A	/
2	30%	500ms	0/90/180/270	3	B	/
3	100%	5000ms	0/90/180/270	3	B	/

Test Result: Pass

EXHIBIT 1 - PRODUCT LABELING

Proposed CE Label Format

<p>ITE Power Supply Model: GT-96600-7056-T3-AP Brand: GlobTek Importer Name: XXX Importer Address: XXX 1. GlobTek, Inc. 2. GlobTek (Suzhou) Co., Ltd 1. 186 Veterans Dr. Northvale, NJ 07647 USA 2. Building 4, No. 76, Jin Ling East Rd., Suzhou Industrial Park, Suzhou, JiangSu 215021, China</p>	  
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Specifications: Text is Black in color and is justified. Labels are printed in indelible ink on permanent adhesive backing or silk-screened onto the EUT or shall be affixed at a conspicuous location on the EUT. The 'CE' marking must be affixed to the EUT or to its data plate. Where this is not possible or not warranted on account of the nature of the apparatus, it must be affixed to the packaging, if any, and to the accompanying documents. The 'CE' marking is allowed less than 5 mm but must clear. If the 'CE' marking is reduced or enlarged the proportions given in the above graduated drawing must be respected. The Importer name, address and Manufacturer name and address should indicate on marking label or packaging or in a document accompanying

Proposed Label Location on EUT

CE Label Location



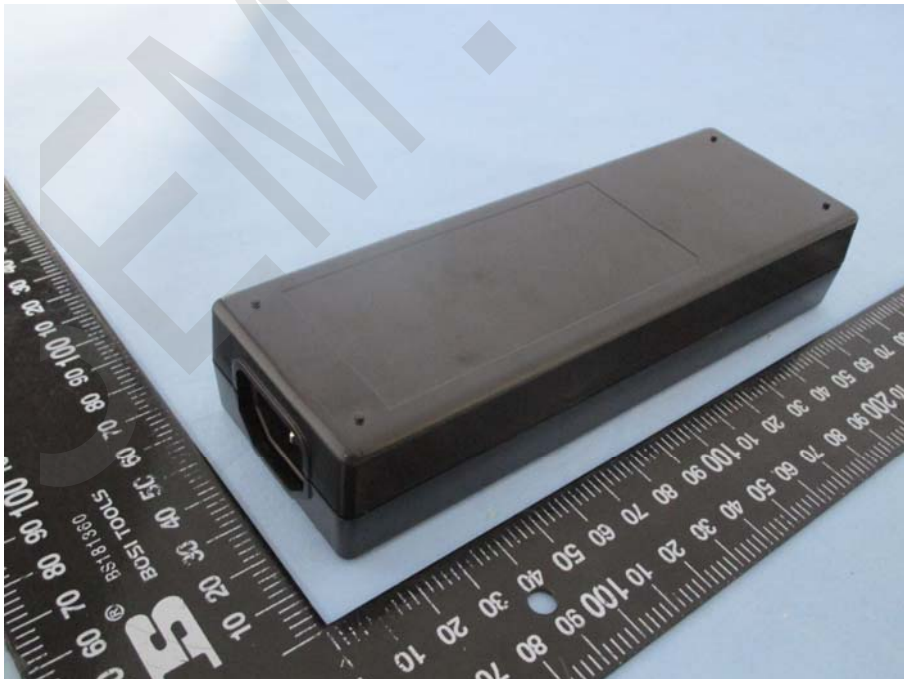
EXHIBIT 2 - EUT PHOTOGRAPHS

EUT View 1



EUT View 2

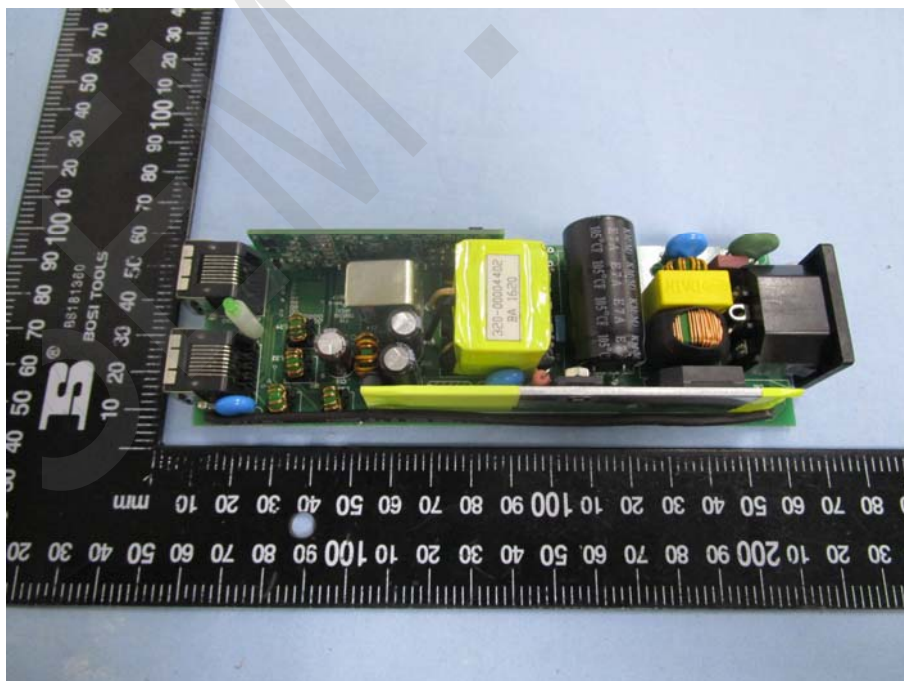


EUT View 3**EUT View 4**

EUT Housing and Board View 1



Solder Board-Component View 1



Solder Board-Component View 2

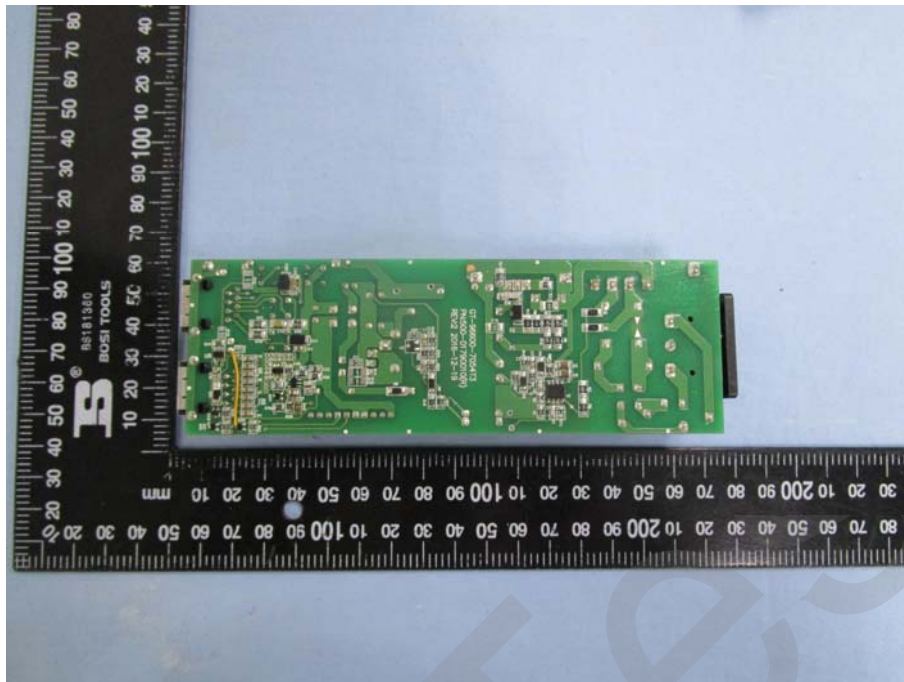
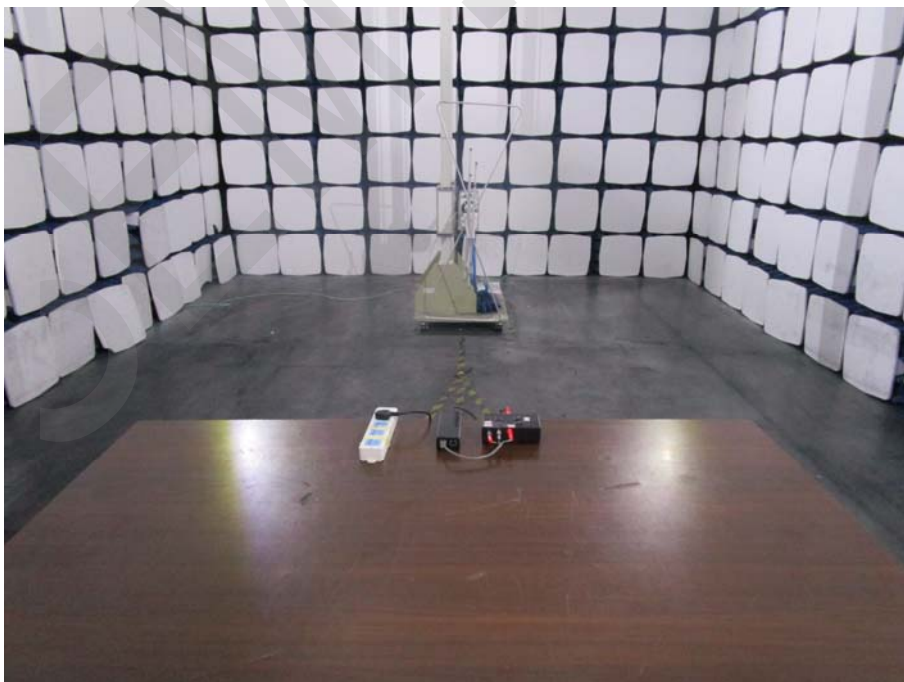


EXHIBIT 3 - TEST SETUP PHOTOGRAPHS

Conduction Emission Test View



Radiation Emission Test View



Harmonic/Flicker Test View



IEC61000-4-2 Test View



IEC61000-4-3 Test View



IEC61000-4-4/5/11 Test View



IEC61000-4-6 Test View

******* END OF REPORT *******